

[54] CIRCUIT TESTER

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[**] Term: 14 Years

[21] Appl. No.: 76,935

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[52] U.S. Cl. D10/78

[58] Field of Search D10/75, 78, 103; 324/60 R, 115, 72.5, 149, 133, 158 F, 158 P, 158 R, 122, 216, 263, 378, 508, 509, 510, 511; 338/36, 37, 38, 226, 228, 229, 230, 232, 233, 234

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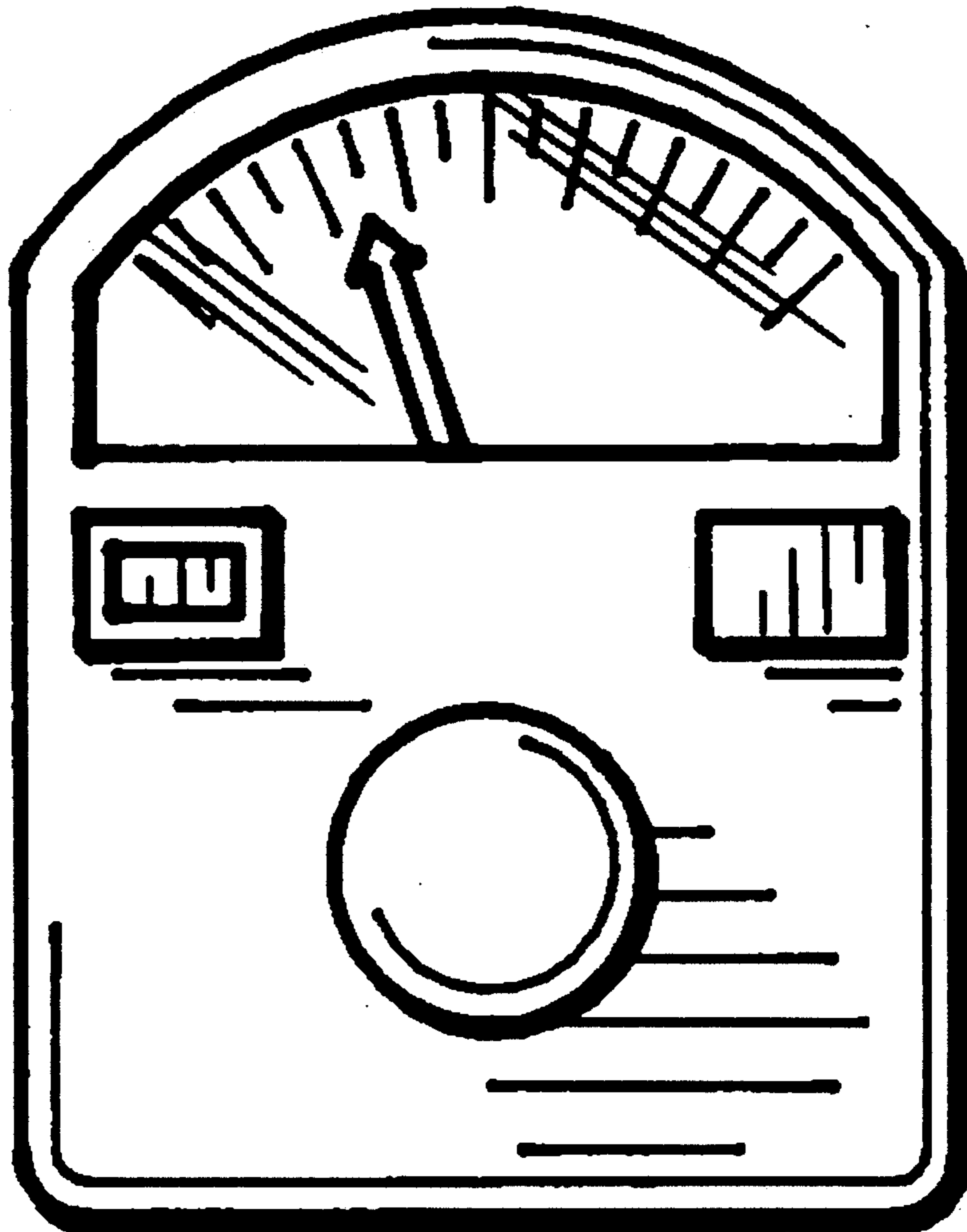
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[57] CLAIM

The ornamental design for a circuit tester, as shown and described.

DESCRIPTION

FIG. 1 is a front elevational view of a circuit tester showing my new design;
FIG. 2 is a rear elevational view;
FIG. 3 is a left side elevational view;
FIG. 4 is a right side elevational view;
FIG. 5 is a top plan view; and
FIG. 6 is a bottom plan view thereof.



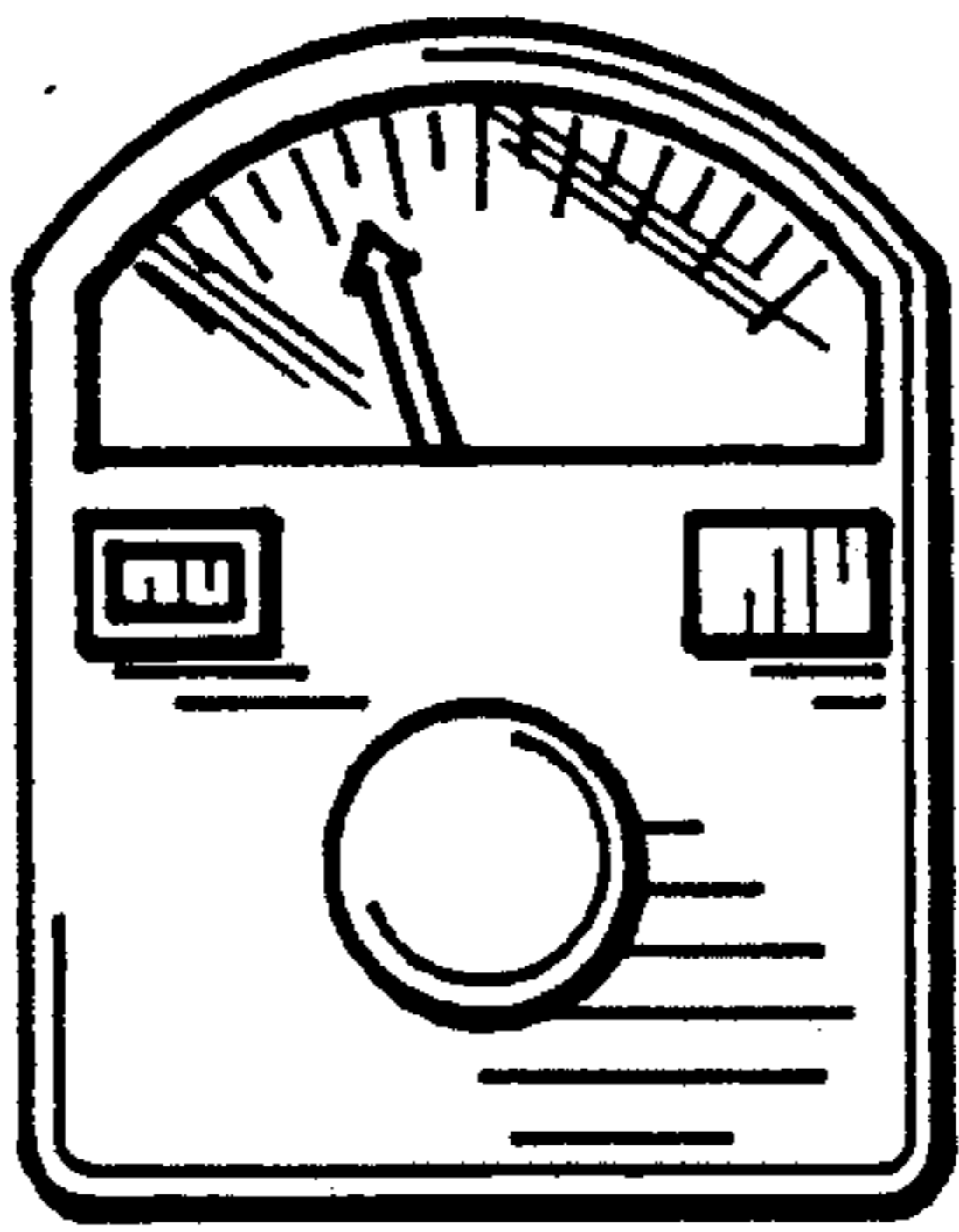


Fig. 1

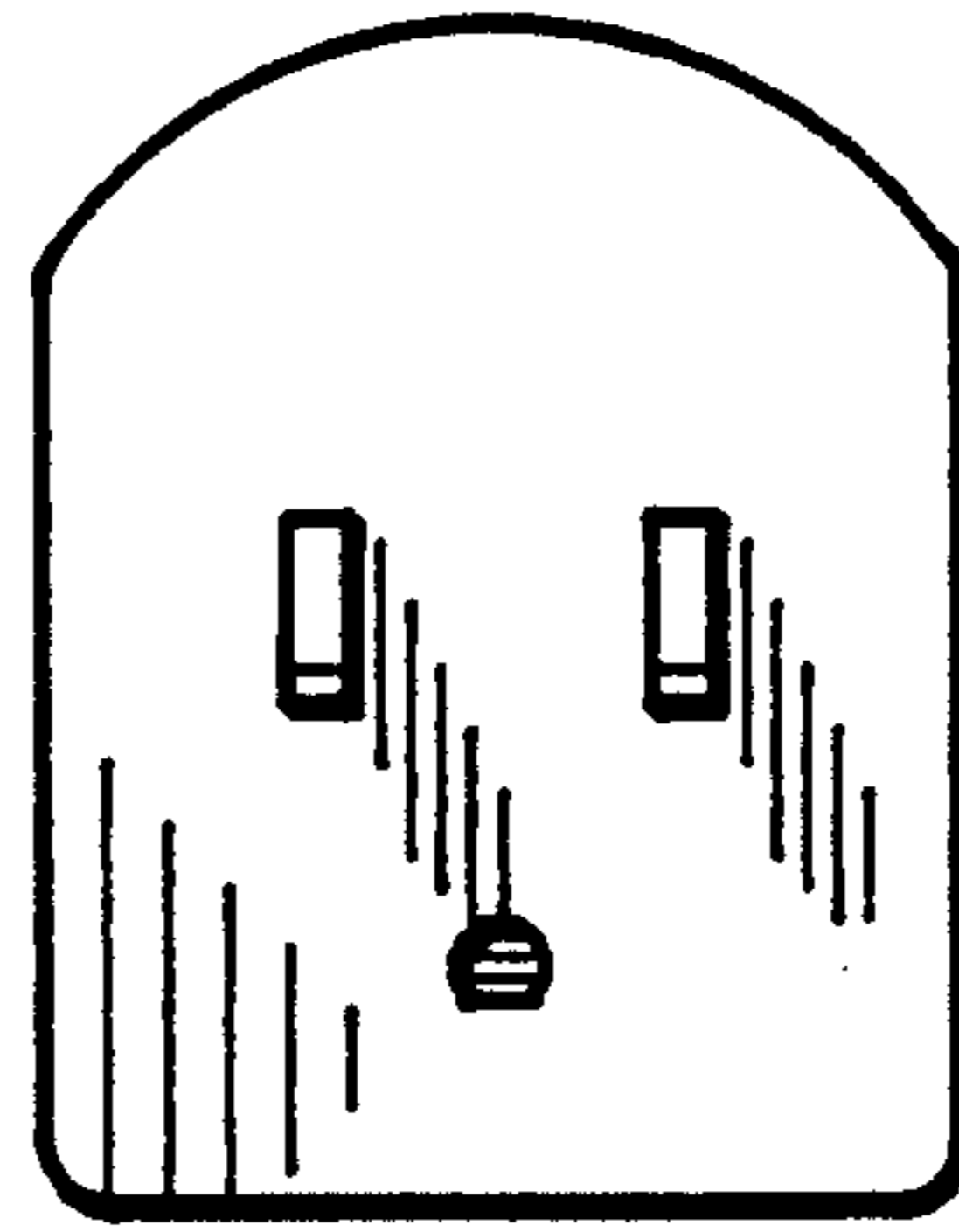


Fig. 2

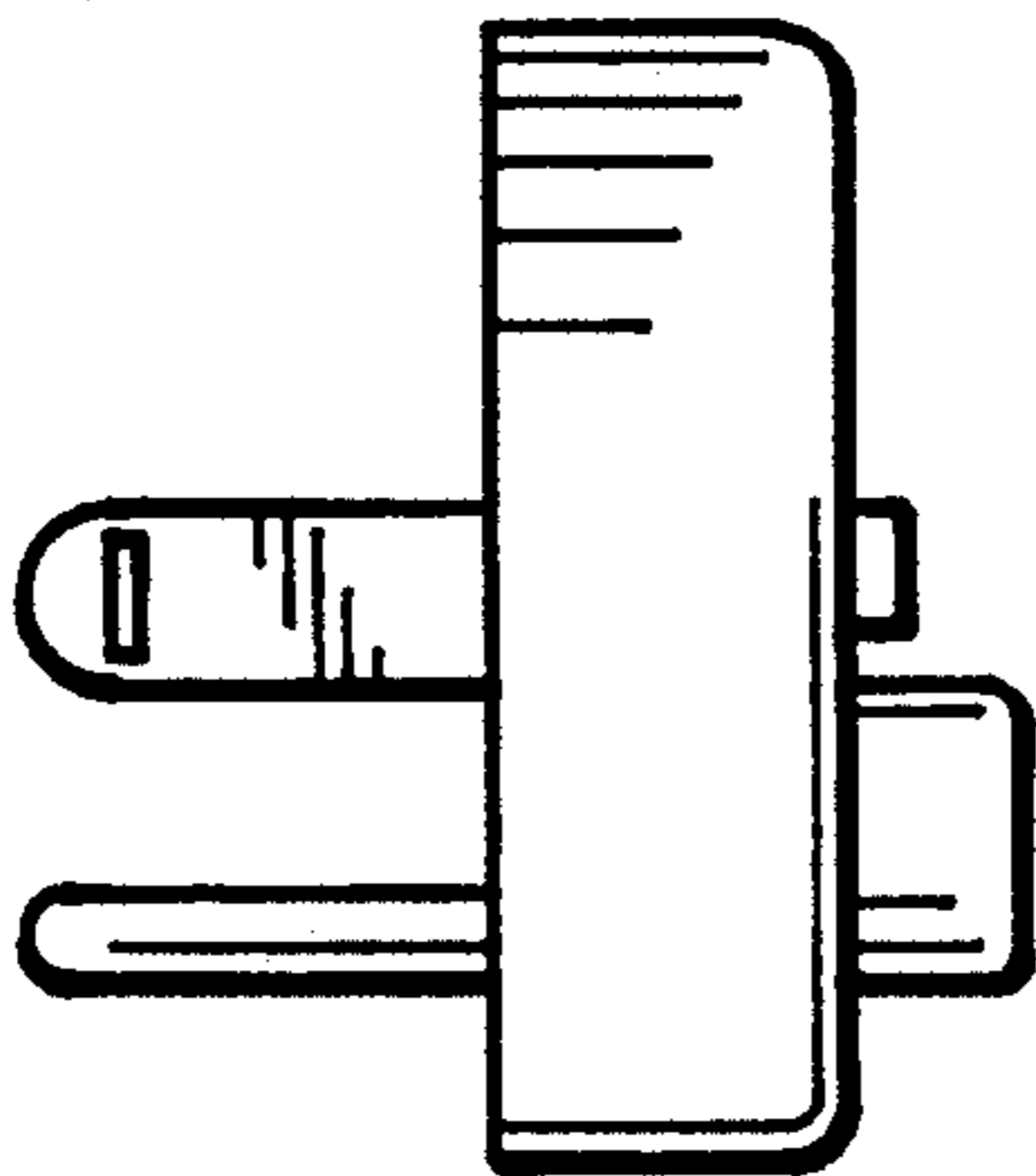


Fig. 3

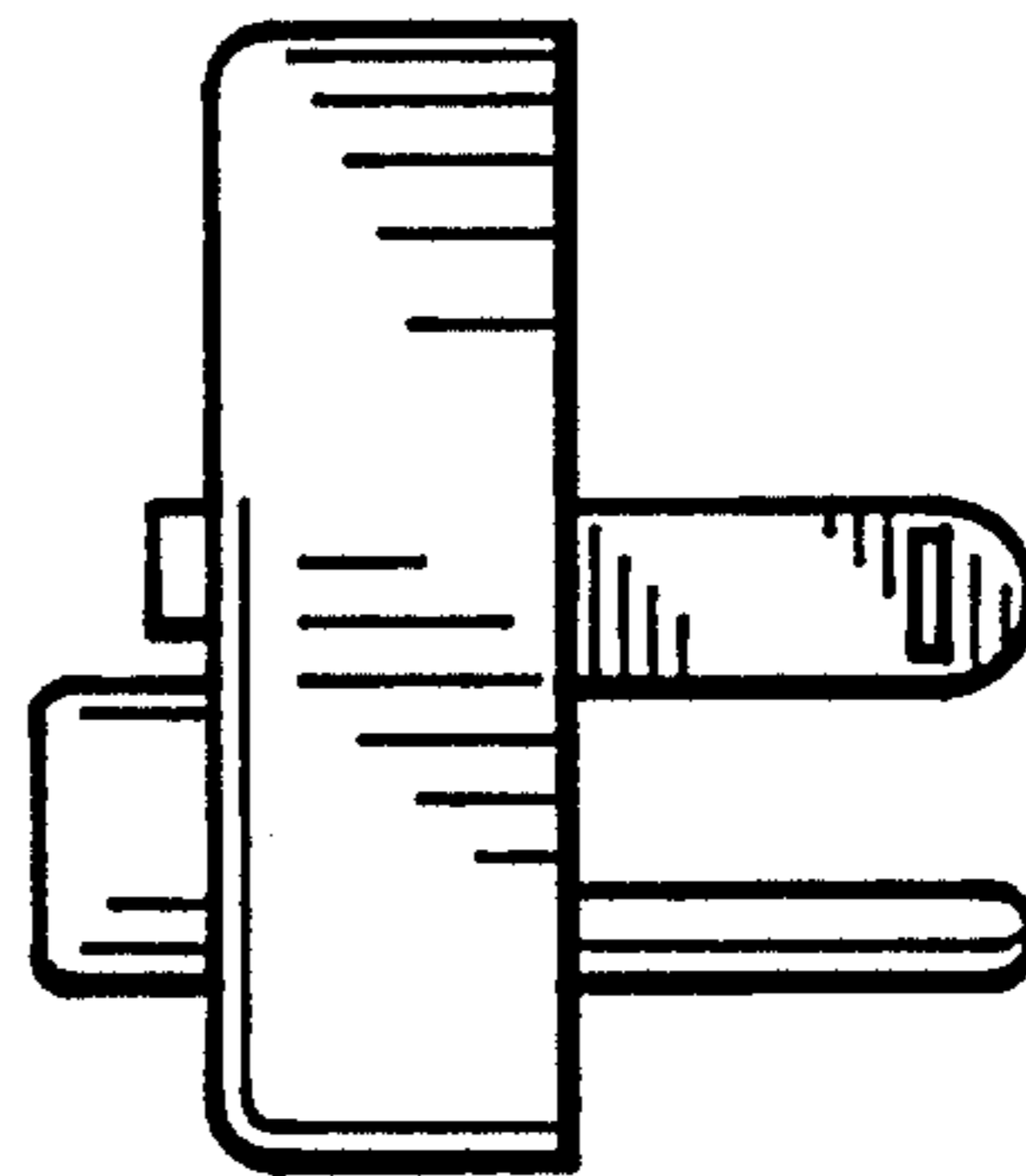


Fig. 4

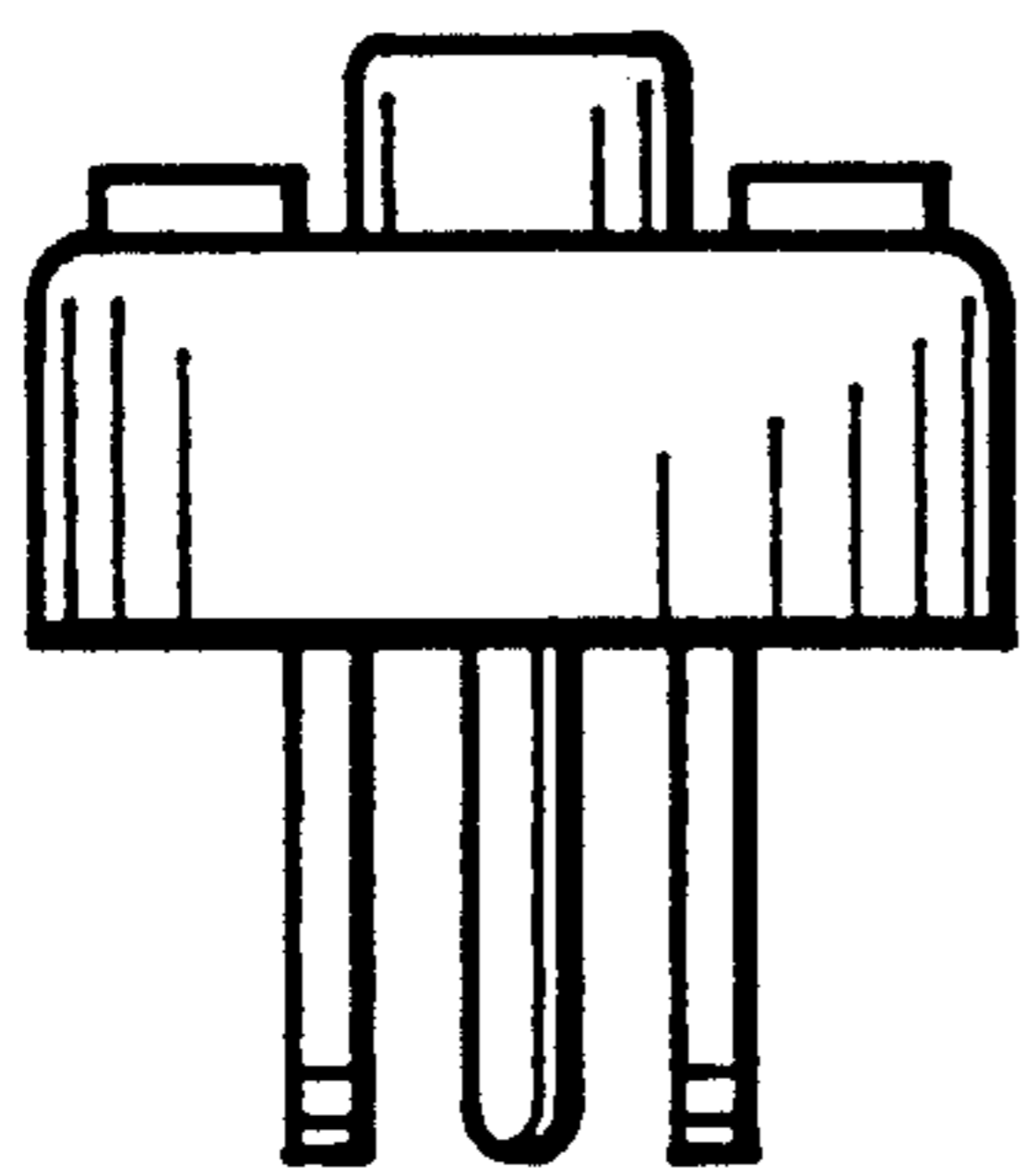


Fig. 5

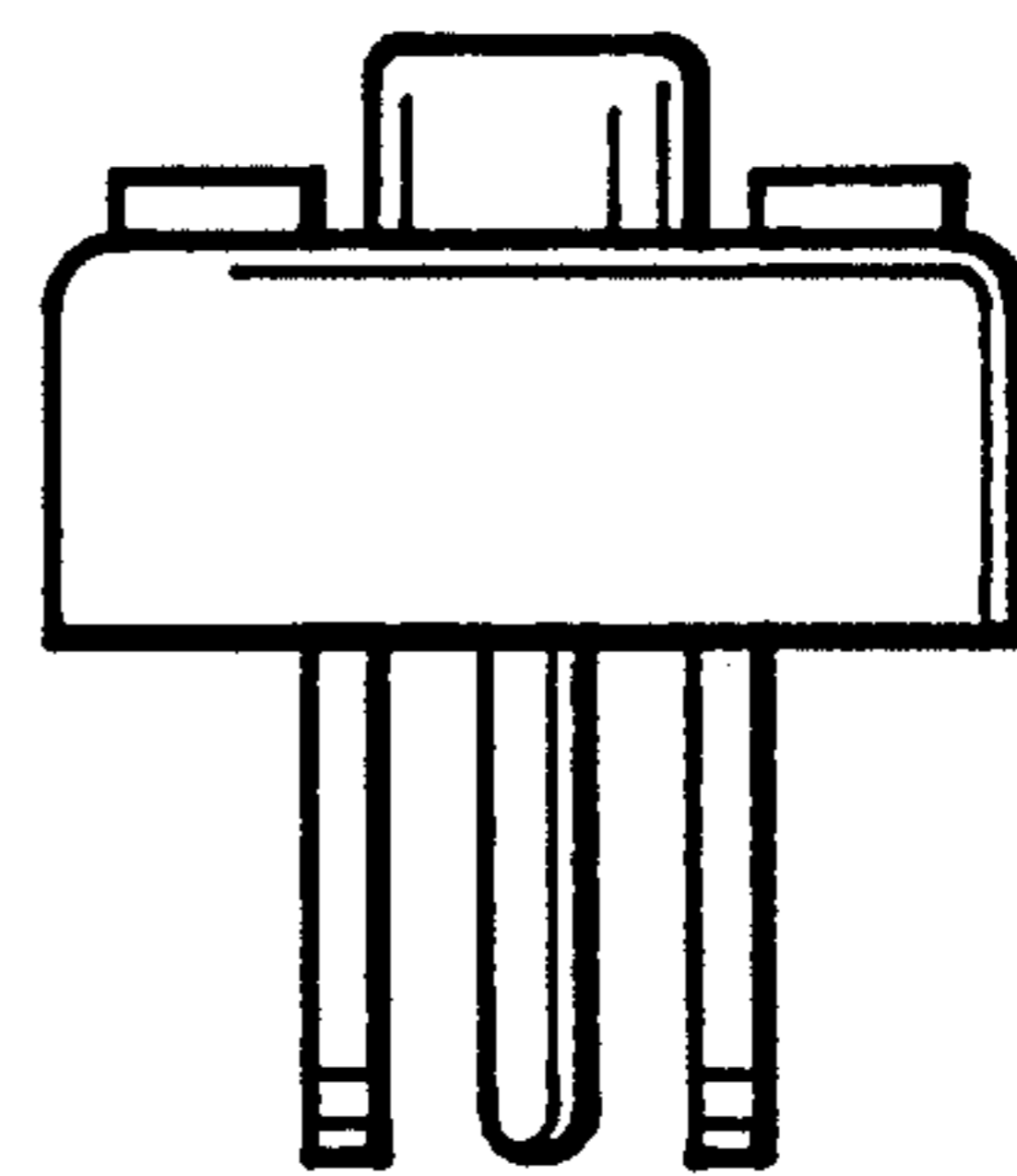


Fig. 6